

10/527410

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Ian SAUNDERS et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed March 11, 2005

Examiner

METHOD FOR MEASURING CONTOUR VARIATIONS

**INFORMATION DISCLOSURE STATEMENT
(SUBMISSION CONCURRENT WITH THE
FILING OF A NEW PATENT APPLICATION)**

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 11, 2005

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

- ☐ Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- ☐ Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- ☒ This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

III. CONCISE EXPLANATION OF THE RELEVANCE **DT09 Rec'd PCT/PTO 11 MAR 2005**
 (check at least one box)

a. ☐ **DOCUMENTS IN THE ENGLISH LANGUAGE**

The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.

b. ☐ **DOCUMENTS NOT IN THE ENGLISH LANGUAGE**

A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:

c. ☒ **FOREIGN SEARCH REPORT OR ACTION**

An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).

d. ☐ **OTHER**

The following additional information is provided for the Examiner's consideration.

FEES

This Information Disclosure Statement is being filed concurrently with the filing of a new patent application; therefore, no fee is required.

If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned.

Respectfully submitted,

YOUNG & THOMPSON

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Enclosures: ☒ Form PTO-1449(s)
☐ Documents
☒ Foreign Search Report
☐ Other: _____

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attorney Docket No.:
2004-1038

Application No.:
NEW NATIONAL PHASE

Applicant:
Ian SAUNDERS et al.

10/527410

Filing Date:
March 11, 2005

Group Art Unit:

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	HEDSER VAN BRUG: "Temporal phase unwrapping and its application in shearography systems" APPLIED OPTICS, vol. 37, no. 28, 1 October 1998 (1998-10-01), pages 6701-6706, XP002244333 cited in the applications page 6705; figures 6,7
	PATENT ABSTRACTS OF JAPAN, vol. 017, no. 132 (P-1504), 18 March 1993 (1993-03-18) - & JP 04 310847 A (OLYMPUS OPTICAL CO LTD), 2 November 1992 (1992-11-02) abstract; figure 2

EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* English language abstract provided for the Examiner's convenience